

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/063,775 LIN, HAO-HSING	
		Examiner	Art Unit Christopher B. Shin	2182 Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,526,515	02-2003	Charles et al.	713/300
	B	US-6,199,122	03-2001	Kobayashi, Toshiya	710/36
	C	US-6,505,267	01-2003	Luke et al.	710/315
	D	US-2005/0060479	03-2005	Deng et al.	710/306
	E	US-2003/0154340	08-2003	Bolt et al.	710/305
	F	US-2001/0013079	08-2001	Luke et al.	710/129
	G	US-6,845,422	01-2005	Shimada et al.	710/305
	H	US-6,006,295	12-1999	Jones et al.	710/62
	I	US-6,718,424	04-2004	Cruz, Claude A.	710/315
	J	US-6,523,081	02-2003	Karlsson et al.	710/305
	K	US-6,785,760	08-2004	Asselin, Albert Andre	710/315
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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